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Docket No. 49304 (70840)

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

APPLICANT(S): X. Zhang and N. Kubo

U.S. SERIAL NO.: 09/391,473

GROUP: 2612

FILED: September 8, 1999

EXAMINER: J. Whipkey

FOR: PIXEL DEFECT DETECTOR FOR SOLID-STATE IMAGING DEVICE

**CERTIFICATE OF FACSIMILE TRANSMISSION**

I hereby certify that this paper (along with any paper referred to as being attached or enclosed) is being transmitted by facsimile to the U.S. Patent & Trademark Office by facsimile number 571-273-8300 on May 3, 2006.

By:   
Steven M. Jensen

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

**RESPONSE TO OFFICE ACTION**

Applicants are in receipt of the Office Action dated February 8, 2006 of the above-referenced application. Applicants respond to the Office Action as follows.

Claims 1-6 and 9-19 are pending in the application.

As recited in independent claim 1, a pixel defect detector includes a calculation section for obtaining output characteristics for at least three amounts of incident light. An advantage of this feature is that least squares analysis can be used in determining the photoelectric coefficient and the offset output level. Use of the least squares method is described on page 14, lines 3-12 of the specification.

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